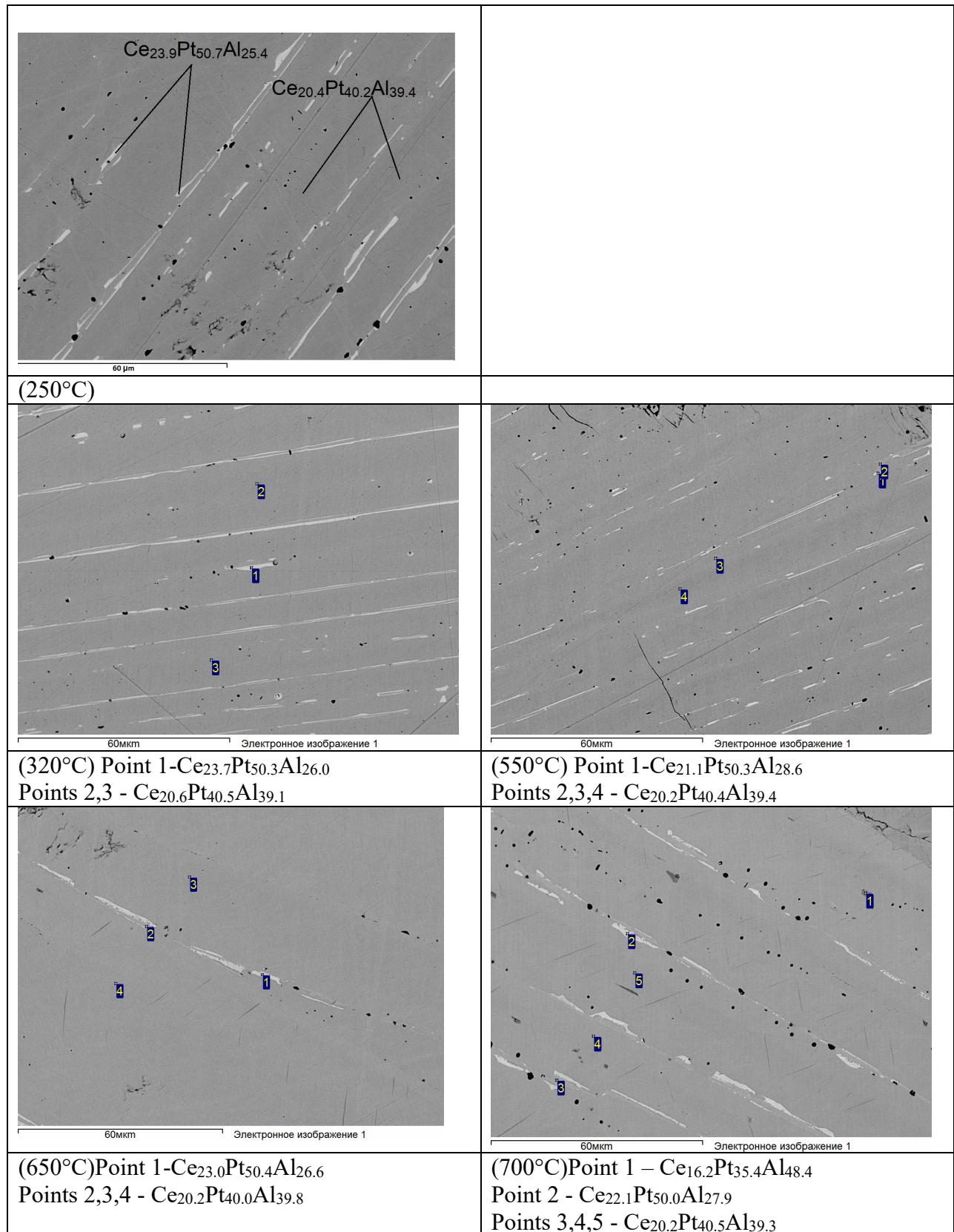
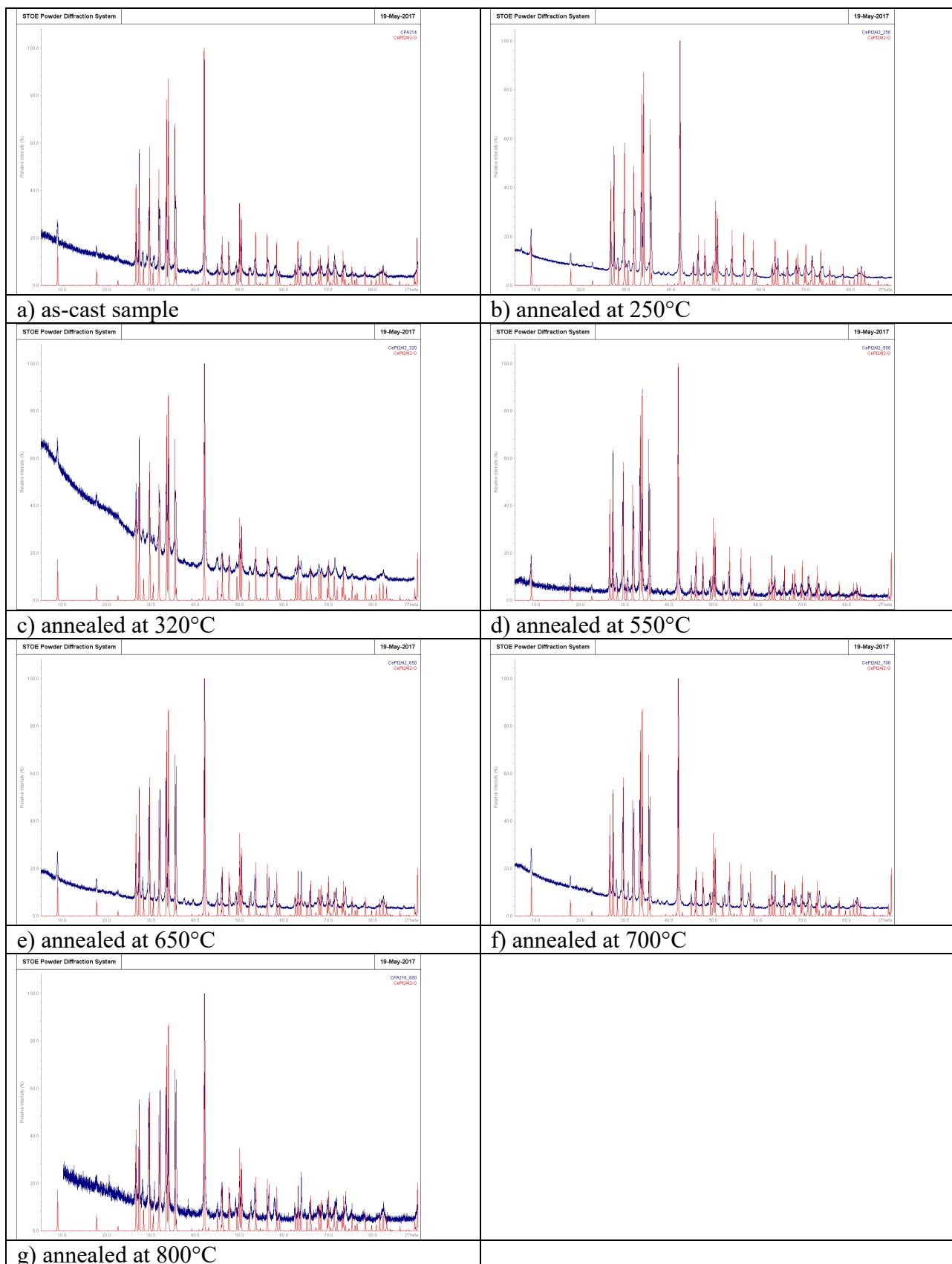
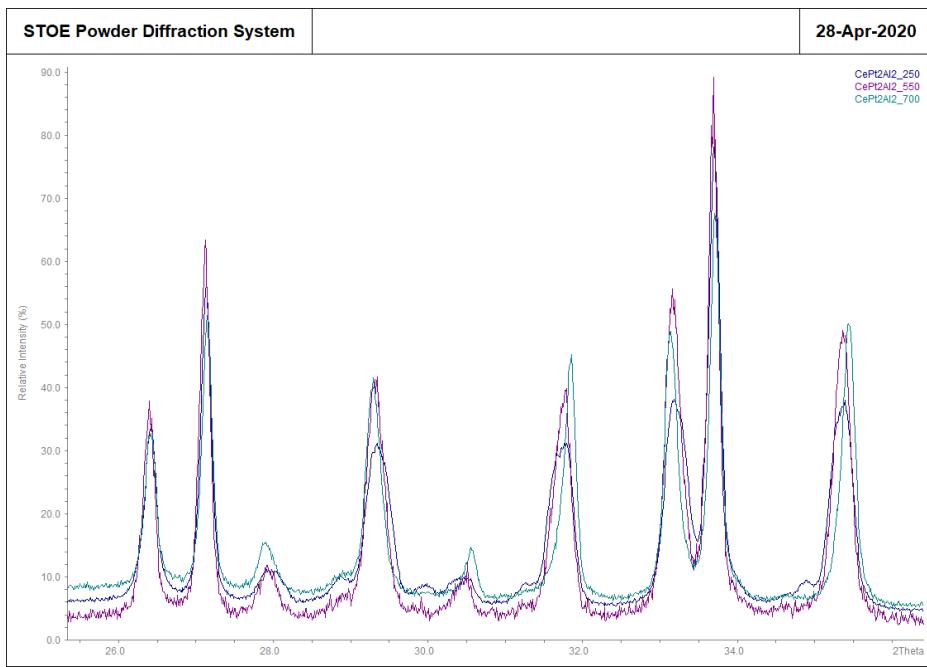


**S1.** Microstructure of Ce<sub>20.0</sub>Pt<sub>40.0</sub>Al<sub>40.0</sub> (at.%) samples annealed at 250°C, 320°C, 550°C, 650°C, 700°C



**S2.** XRD patterns of Ce<sub>20.0</sub>Pt<sub>40.0</sub>Al<sub>40.0</sub> (at.%) samples annealed at different temperatures (a-g). XRD patterns in the 25.5 – 36.5 2θ range showing dependence of FWHM on the annealing temperature (h).

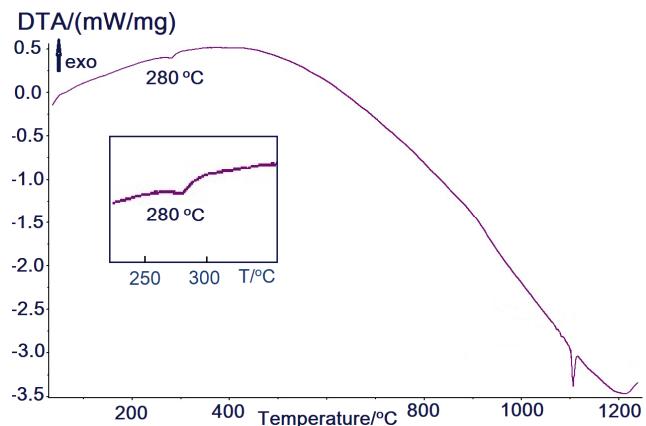




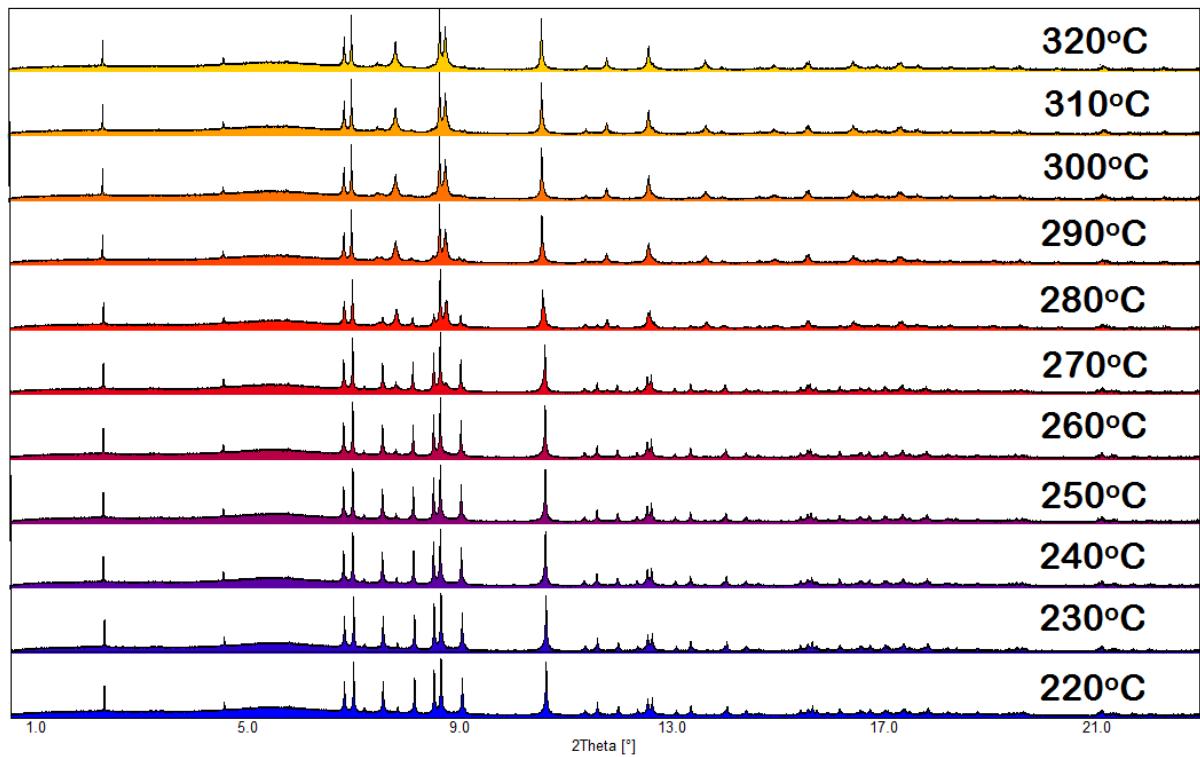
h)

### S3.

Heating DTA thermogram of CePt<sub>2</sub>Al<sub>2</sub> sample annealed at 550 °C.



**S4.** Structural transition of the low-temperature orthorhombic CePt<sub>2</sub>Al<sub>2</sub> to the high-temperature tetragonal modification. XRD patterns at 220, 230, 240, 250, 260, 270, 280, 290, 300, 310, 320°C (a); a projection of XRD patterns (b).



a)

Projection of XRD patterns at 220, 230, 240, 250, 260, 270, 280, 290, 300, 310, 320°C(b).

